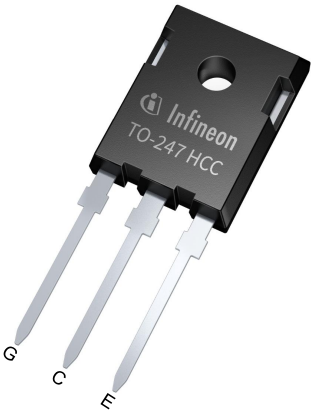
Final datasheet

High speed and low saturation voltage 750 V TRENCHSTOP™ IGBT7 technology co-packed with soft and fast recovery Emitter Controlled 7 diode

Features

- V_{CE} = 750 V
- I_C = 50 A
- Low switching losses
- Very low collector-emitter saturation voltage V_{CEsat}
- Very soft, fast recovery antiparallel diode
- Smooth switching behavior
- Humidity robustness
- Optimized for hard switching, two- and three-level topologies
- Complete product spectrum and PSpice Models: http://www.infineon.com/igbt/



Lead-free
Green
Halogen-free
RoHS

Potential applications

- Industrial UPS
- EV Charging
- String inverter
- Energy storage systems (ESS)

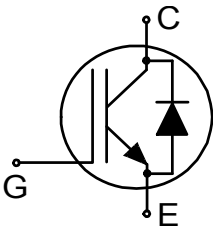
Product validation

- Qualified for industrial applications according to the relevant tests of JEDEC47/20/22

Description

Package pin definition:

- Pin G – Gate
- Pin C & backside – Collector
- Pin E – Emitter



Type	Package	Marking
IKWH50N75EH7	PG-TO247-3-U04	K50GEH7

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1 Package

Table 1 Characteristic values

Parameter	Symbol	Note or test condition	Values			Unit
			Min.	Typ.	Max.	
Internal emitter inductance measured 5 mm (0.197 in.) from case	L_E			13		nH
Storage temperature	T_{stg}		-55		150	°C
Soldering temperature	T_{sold}	wave soldering 1.6 mm (0.063 in.) from case for 10 s			260	°C
Mounting torque	M	M3 screw, Maximum of mounting processes: 3			0.6	Nm
Thermal resistance, junction-ambient	$R_{th(j-a)}$				40	K/W
IGBT thermal resistance, junction-case	$R_{th(j-c)}$			0.46	0.6	K/W
Diode thermal resistance, junction-case	$R_{th(j-c)}$			0.61	0.8	K/W

2 IGBT

Table 2 Maximum rated values

Parameter	Symbol	Note or test condition		Values	Unit
Collector-emitter voltage	V_{CE}	$T_{vj} \geq 25$ °C		750	V
DC collector current, limited by T_{vjmax}	I_C	limited by bondwire	$T_c = 25$ °C	80	A
			$T_c = 100$ °C	67	
Pulsed collector current, t_p limited by T_{vjmax}	I_{Cpulse}			200	A
Turn-off safe operating area		$V_{CE} \leq 750$ V, $t_p \leq 1$ µs, $T_{vj} \leq 175$ °C		200	A
Gate-emitter voltage	V_{GE}			±20	V
Transient gate-emitter voltage	V_{GE}	$t_p \leq 10$ µs, $D < 0.01$		±30	V
Power dissipation	P_{tot}		$T_c = 25$ °C	250	W
			$T_c = 100$ °C	125	

Table 3 Characteristic values

Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Collector-emitter saturation voltage	V_{CEsat}	I_C = 50 A, V_{GE} = 15 V	T_{vj} = 25 °C		1.45	1.75	V
			T_{vj} = 175 °C		1.75		
Gate-emitter threshold voltage	V_{GEth}	I_C = 0.44 mA, V_{CE} = V_{GE}		3.2	4	4.8	V
Zero gate-voltage collector current	I_{CES}	V_{CE} = 750 V, V_{GE} = 0 V	T_{vj} = 25 °C			15	µA
			T_{vj} = 175 °C		1500		
Gate-emitter leakage current	I_{GES}	V_{CE} = 0 V, V_{GE} = 20 V				100	nA
Transconductance	g_{fs}	I_C = 50 A, V_{CE} = 20 V			65		S
Input capacitance	C_{ies}	V_{CE} = 25 V, V_{GE} = 0 V, f = 100 kHz			2560		pF
Output capacitance	C_{oes}	V_{CE} = 25 V, V_{GE} = 0 V, f = 100 kHz			79		pF
Reverse transfer capacitance	C_{res}	V_{CE} = 25 V, V_{GE} = 0 V, f = 100 kHz			9.6		pF
Gate charge	Q_G	V_{CC} = 600 V, I_C = 50 A, V_{GE} = 15 V			105		nC
Turn-on delay time	$t_{d(on)}$	V_{CC} = 400 V, V_{GE} = 0/15 V, $R_{G(on)}$ = 10 Ω, $R_{G(off)}$ = 10 Ω	T_{vj} = 25 °C, I_C = 50 A		18		ns
			T_{vj} = 175 °C, I_C = 50 A		18		
Rise time (inductive load)	t_r	V_{CC} = 400 V, V_{GE} = 0/15 V, $R_{G(on)}$ = 10 Ω, $R_{G(off)}$ = 10 Ω	T_{vj} = 25 °C, I_C = 50 A		18		ns
			T_{vj} = 175 °C, I_C = 50 A		19		
Turn-off delay time	$t_{d(off)}$	V_{CC} = 400 V, V_{GE} = 0/15 V, $R_{G(on)}$ = 10 Ω, $R_{G(off)}$ = 10 Ω	T_{vj} = 25 °C, I_C = 50 A		141		ns
			T_{vj} = 175 °C, I_C = 50 A		175		
Fall time (inductive load)	t_f	V_{CC} = 400 V, V_{GE} = 0/15 V, $R_{G(on)}$ = 10 Ω, $R_{G(off)}$ = 10 Ω	T_{vj} = 25 °C, I_C = 50 A		30		ns
			T_{vj} = 175 °C, I_C = 50 A		72		
Turn-on energy	E_{on}	V_{CC} = 400 V, V_{GE} = 0/15 V, $R_{G(on)}$ = 10 Ω, $R_{G(off)}$ = 10 Ω	T_{vj} = 25 °C, I_C = 50 A		1.1		mJ
			T_{vj} = 175 °C, I_C = 50 A		1.5		

(table continues...)

Table 3 (continued) Characteristic values

Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Turn-off energy	E_{off}	V_{CC} = 400 V, V_{GE} = 0/15 V, $R_{G(on)}$ = 10 Ω, $R_{G(off)}$ = 10 Ω	T_{vj} = 25 °C, I_C = 50 A		0.6		mJ
			T_{vj} = 175 °C, I_C = 50 A		1.2		
Total switching energy	E_{ts}	V_{CC} = 400 V, V_{GE} = 0/15 V, $R_{G(on)}$ = 10 Ω, $R_{G(off)}$ = 10 Ω	T_{vj} = 25 °C, I_C = 50 A		1.7		mJ
			T_{vj} = 175 °C, I_C = 50 A		2.7		
Operating junction temperature	T_{vj}			-40		175	°C

3 Diode

Table 4 Maximum rated values

Parameter	Symbol	Note or test condition		Values	Unit
Diode forward current, limited by T_{vjmax}	I_F	limited by bondwire	T_c = 25 °C	80	A
			T_c = 100 °C	57	
Diode pulsed current, t_p limited by T_{vjmax}	I_{Fpulse}			200	A
Power dissipation	P_{tot}		T_c = 25 °C	188	W
			T_c = 100 °C	94	

Table 5 Characteristic values

Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Diode forward voltage	V_F	I_F = 50 A	T_{vj} = 25 °C		1.65	2	V
			T_{vj} = 175 °C		1.6		
Diode reverse recovery time	t_{rr}	V_R = 400 V, $R_{G(on)}$ = 10 Ω	T_{vj} = 25 °C, I_F = 50 A		88		ns
			T_{vj} = 175 °C, I_F = 50 A		151		
Diode reverse recovery charge	Q_{rr}	V_R = 400 V, $R_{G(on)}$ = 10 Ω	T_{vj} = 25 °C, I_F = 50 A		1.5		µC
			T_{vj} = 175 °C, I_F = 50 A		3.4		

(table continues...)

Table 5 (continued) Characteristic values

Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Diode peak reverse recovery current	I_{rrm}	V_R = 400 V, $R_{G(on)}$ = 10 Ω	T_{vj} = 25 °C, I_F = 50 A		28.8		A
			T_{vj} = 175 °C, I_F = 50 A		42.8		
Diode peak rate of fall of reverse recovery current	di_{rr}/dt	V_R = 400 V, $R_{G(on)}$ = 10 Ω	T_{vj} = 25 °C, I_F = 50 A		-470		A/µs
			T_{vj} = 175 °C, I_F = 50 A		-380		
Reverse recovery energy	E_{rec}	V_R = 400 V, $R_{G(on)}$ = 10 Ω	T_{vj} = 25 °C, I_F = 50 A		0.35		mJ
			T_{vj} = 175 °C, I_F = 50 A		0.91		
Operating junction temperature	T_{vj}			-40		175	°C

***Note**: For optimum lifetime and reliability, Infineon recommends operating conditions that do not exceed 80% of the maximum ratings stated in this datasheet.*

Electrical Characteristic at T_{vj} = 25°C, unless otherwise specified.

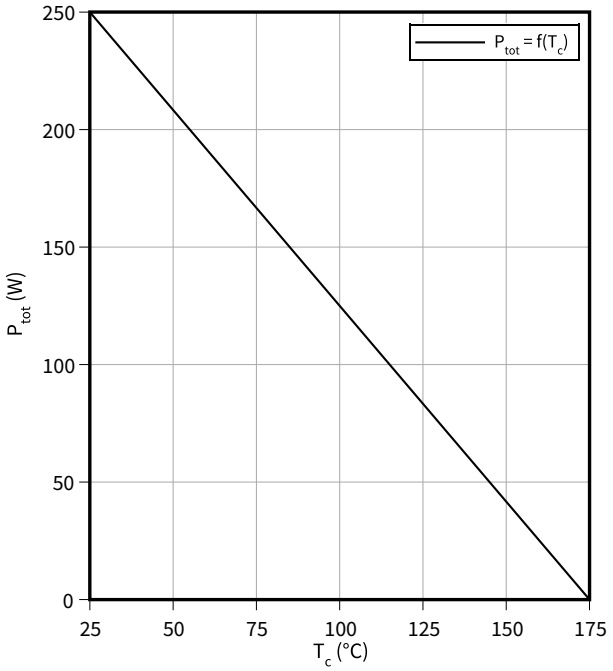
Dynamic test circuit, parasitic inductance L_σ = 8 nH, parasitic capacitor C_σ = 30 pF from Fig. E. Energy losses include “tail” and diode reverse recovery.

4 Characteristics diagrams

Power dissipation as a function of case temperature

$P_{tot} = f(T_c)$

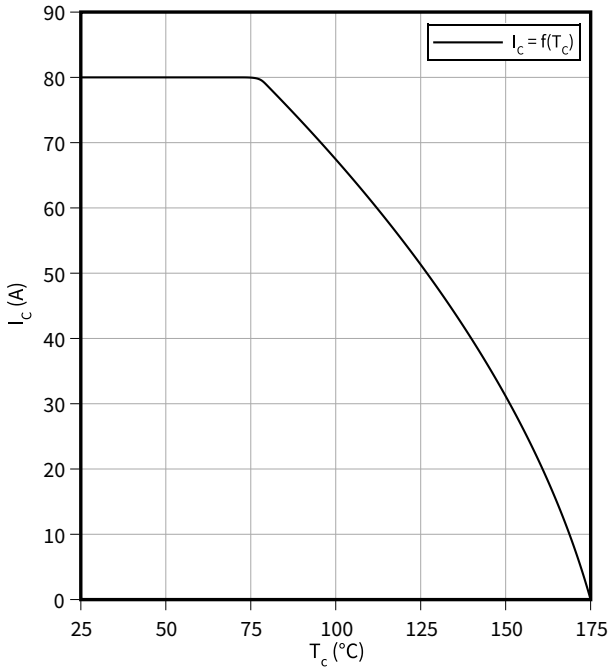
$T_{vj} \leq 175\ °C$



Collector current as a function of case temperature

$I_C = f(T_c)$

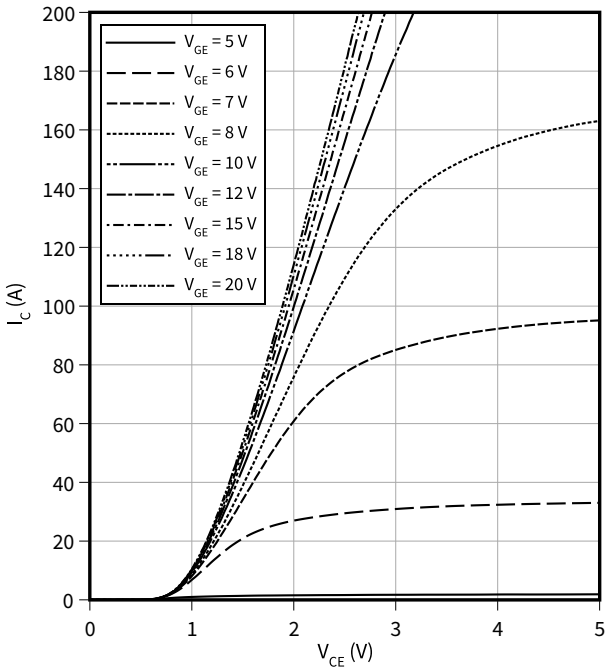
$T_{vj} \leq 175\ °C$, $V_{GE} \geq 15\ V$



Typical output characteristic

$I_C = f(V_{CE})$

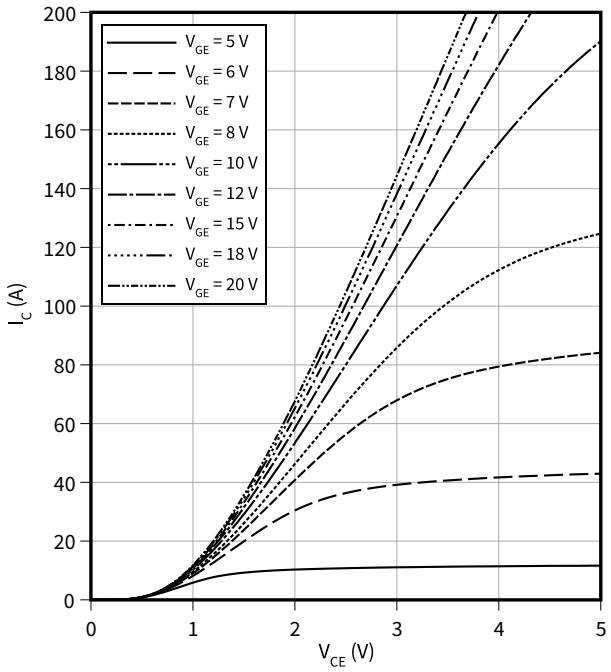
$T_{vj} = 25\ °C$



Typical output characteristic

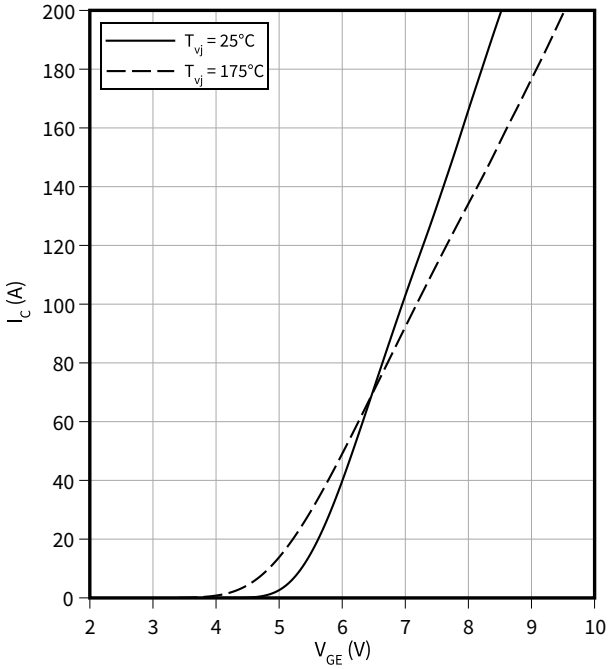
$I_C = f(V_{CE})$

$T_{vj} = 175\ °C$



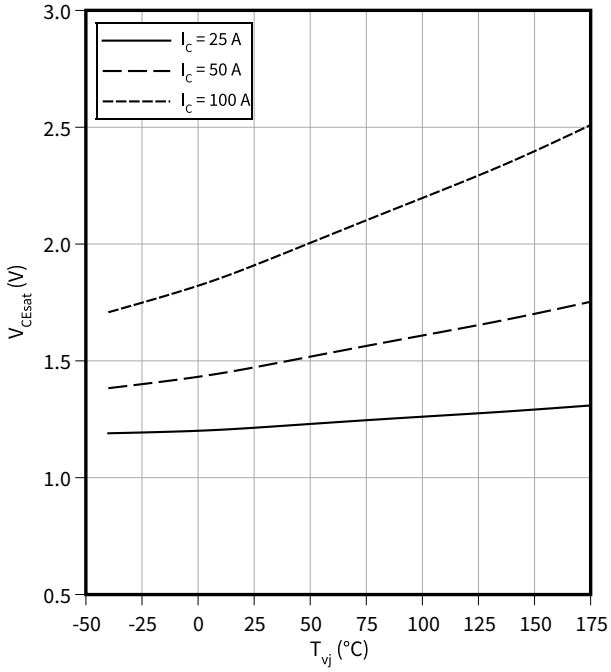
Typical transfer characteristic

$I_C = f(V_{GE})$
$V_{CE} = 20$ V



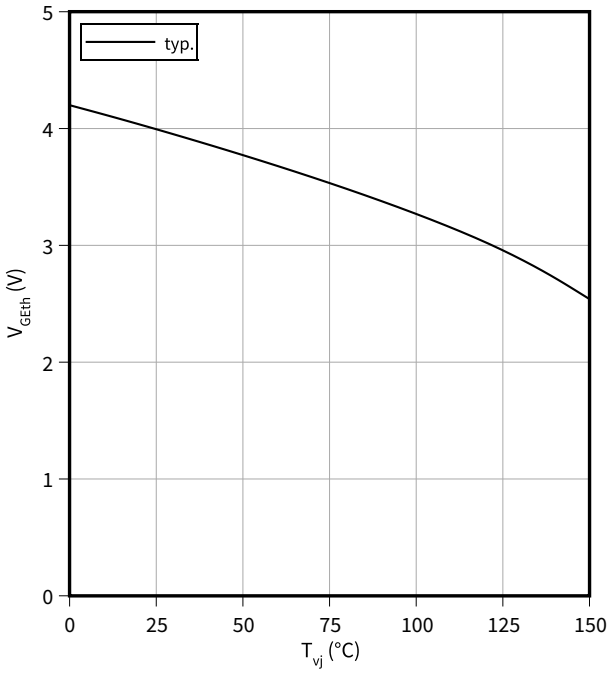
Typical collector-emitter saturation voltage as a function of junction temperature

$V_{CEsat} = f(T_{vj})$
$V_{GE} = 15$ V



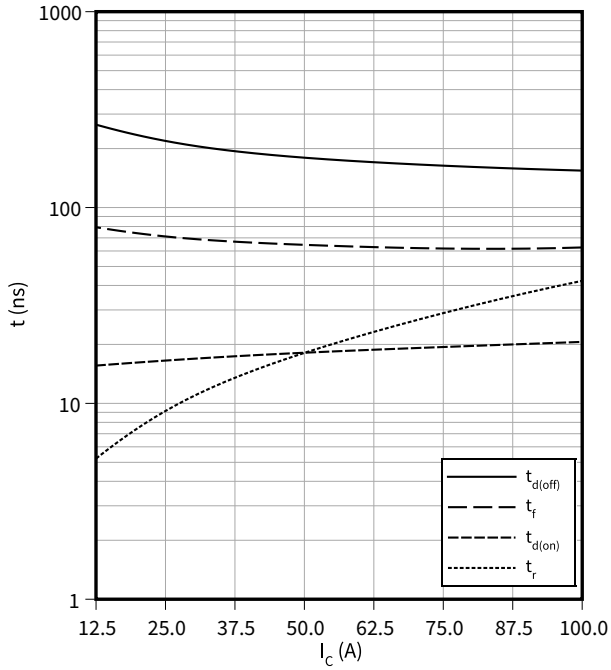
Gate-emitter threshold voltage as a function of junction temperature

$V_{GEth} = f(T_{vj})$
$I_C = 0.44$ mA



Typical switching times as a function of collector current

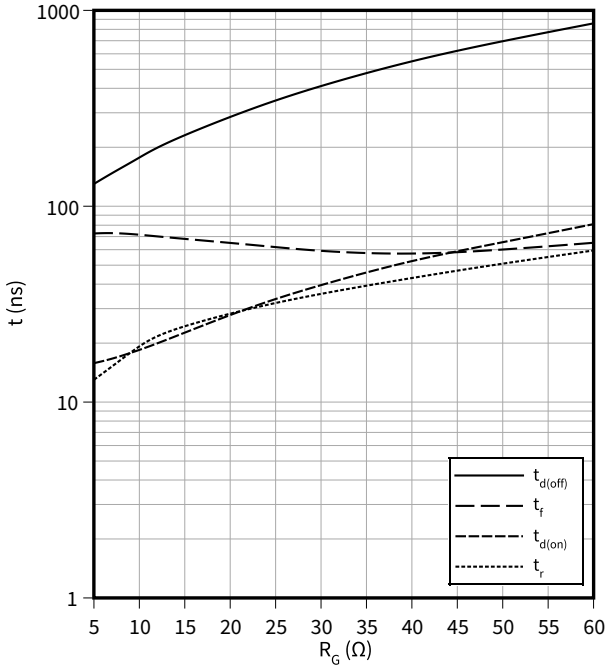
$t = f(I_C)$
$V_{CC} = 400$ V, $T_{vj} = 175$ °C, $V_{GE} = 0/15$ V, $R_G = 10\ \Omega$



Typical switching times as a function of gate resistor

$t = f(R_G)$

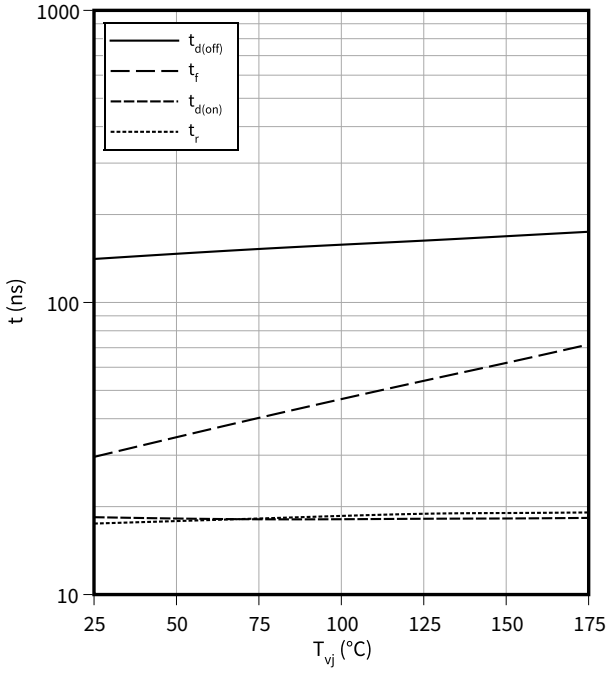
$I_C = 50\ A$, $V_{CC} = 400\ V$, $T_{vj} = 175\ °C$, $V_{GE} = 0/15\ V$



Typical switching times as a function of junction temperature

$t = f(T_{vj})$

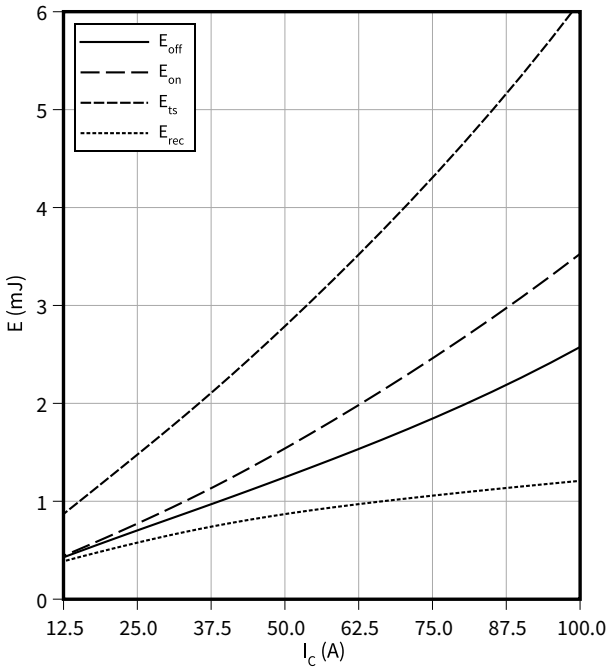
$I_C = 50\ A$, $V_{CC} = 400\ V$, $V_{GE} = 0/15\ V$, $R_G = 10\ Ω$



Typical switching energy losses as a function of collector current

$E = f(I_C)$

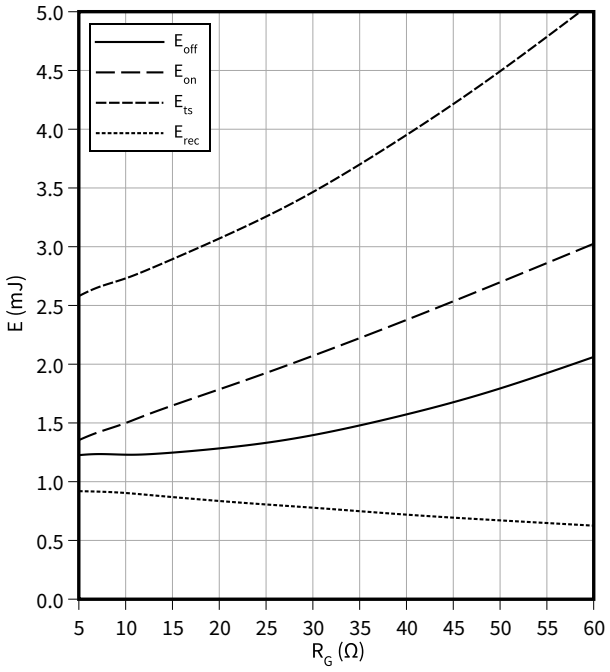
$V_{CC} = 400\ V$, $T_{vj} = 175\ °C$, $V_{GE} = 0/15\ V$, $R_G = 10\ Ω$



Typical switching energy losses as a function of gate resistor

$E = f(R_G)$

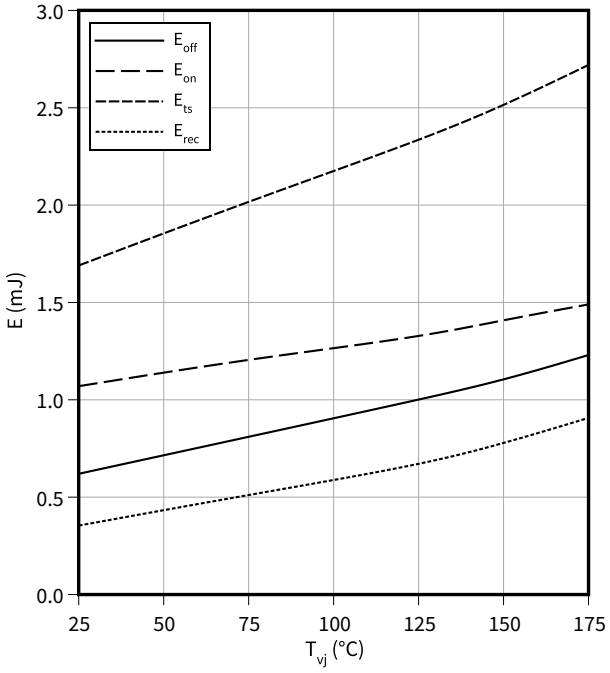
$I_C = 50\ A$, $V_{CC} = 400\ V$, $T_{vj} = 175\ °C$, $V_{GE} = 0/15\ V$



Typical switching energy losses as a function of junction temperature

$E = f(T_{vj})$

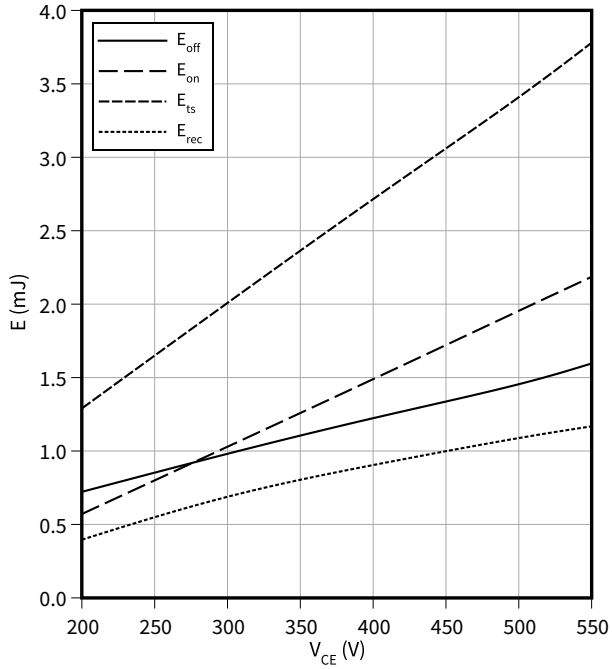
$I_C = 50\ A$, $V_{CC} = 400\ V$, $V_{GE} = 0/15\ V$, $R_G = 10\ \Omega$



Typical switching energy losses as a function of collector emitter voltage

$E = f(V_{CE})$

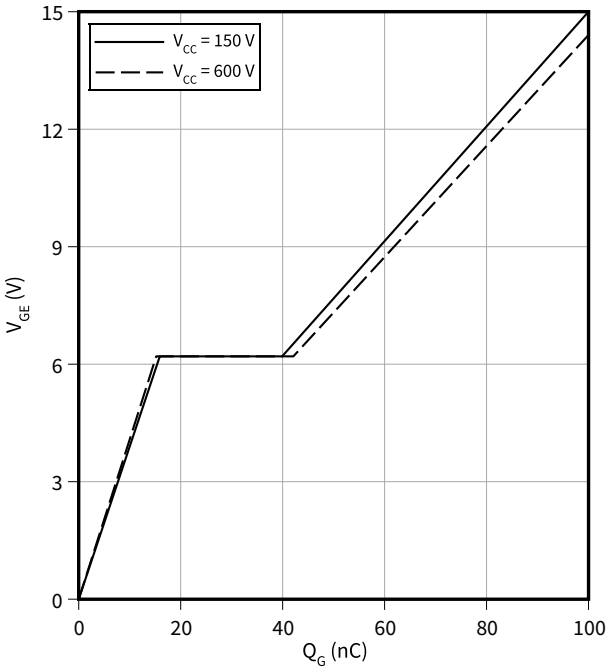
$I_C = 50\ A$, $T_{vj} = 175\ °C$, $V_{GE} = 0/15\ V$, $R_G = 10\ \Omega$



Typical gate charge

$V_{GE} = f(Q_G)$

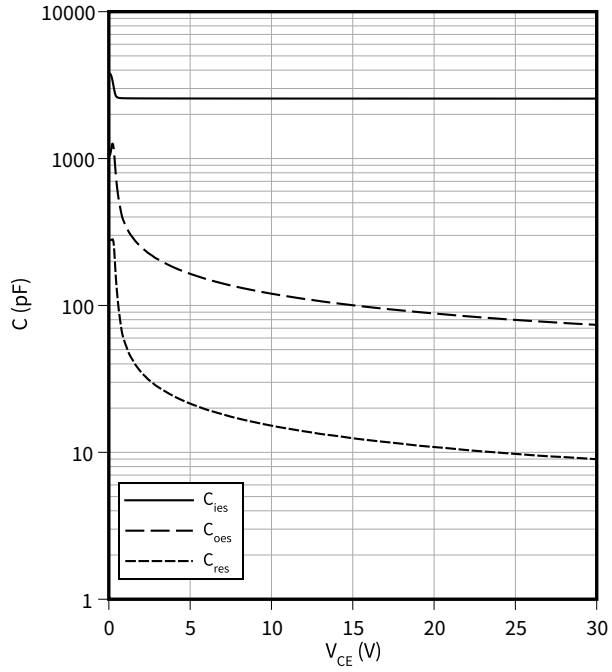
$I_C = 50\ A$



Typical capacitance as a function of collector-emitter voltage

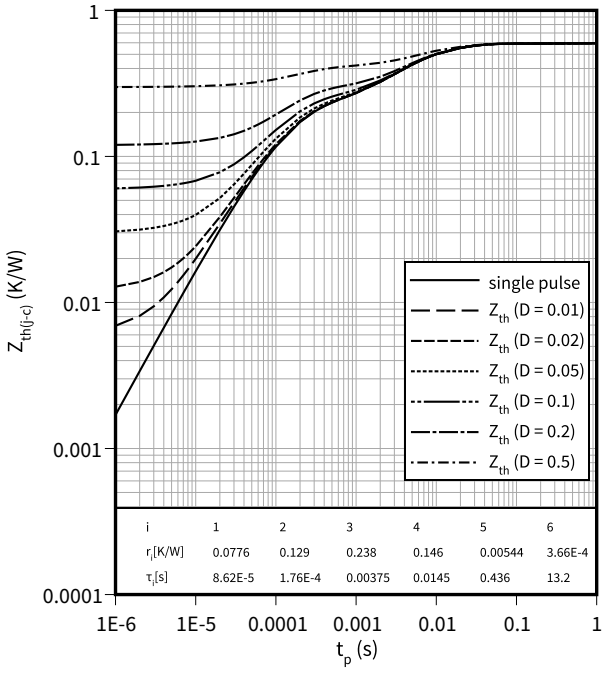
$C = f(V_{CE})$

$f = 100\ kHz$, $V_{GE} = 0\ V$



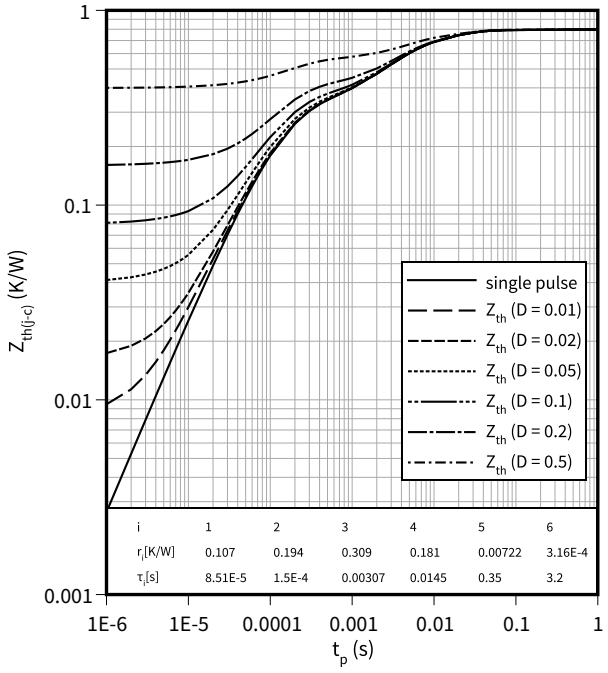
IGBT transient thermal impedance as a function of pulse width

$Z_{th(j-c)} = f(t_p)$
$D = t_p/T$



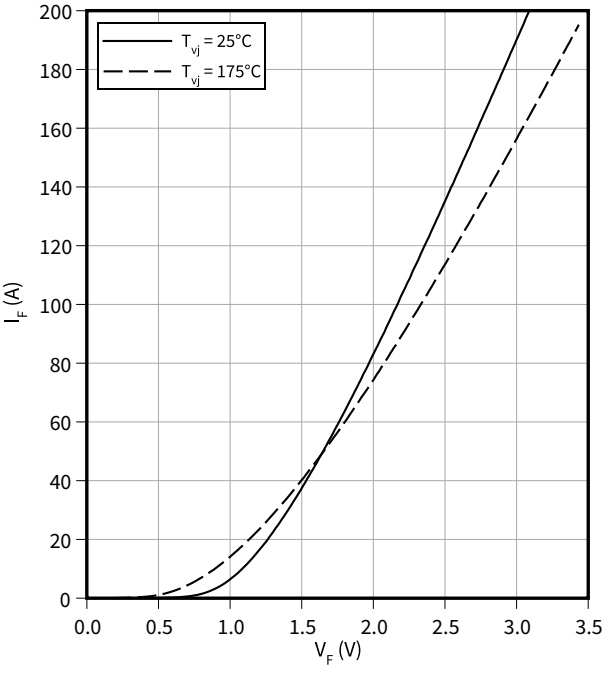
Diode transient thermal impedance as a function of pulse width

$Z_{th(j-c)} = f(t_p)$
$D = t_p/T$



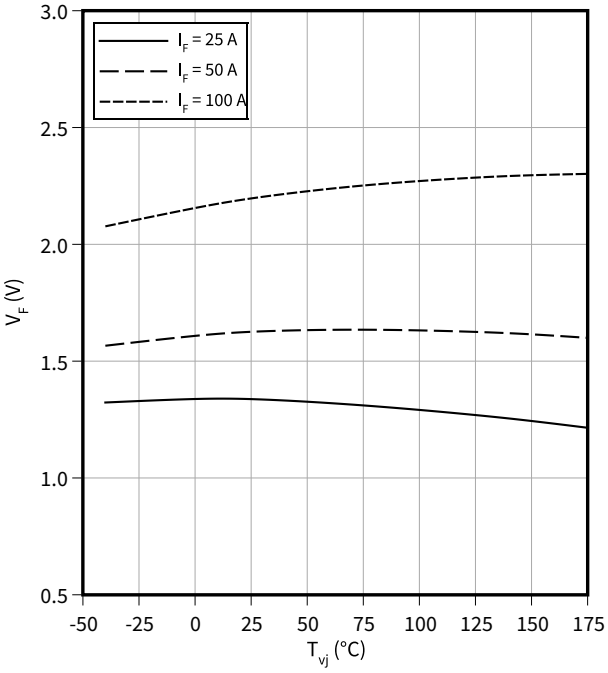
Typical diode forward current as a function of forward voltage

$I_F = f(V_F)$



Typical diode forward voltage as a function of junction temperature

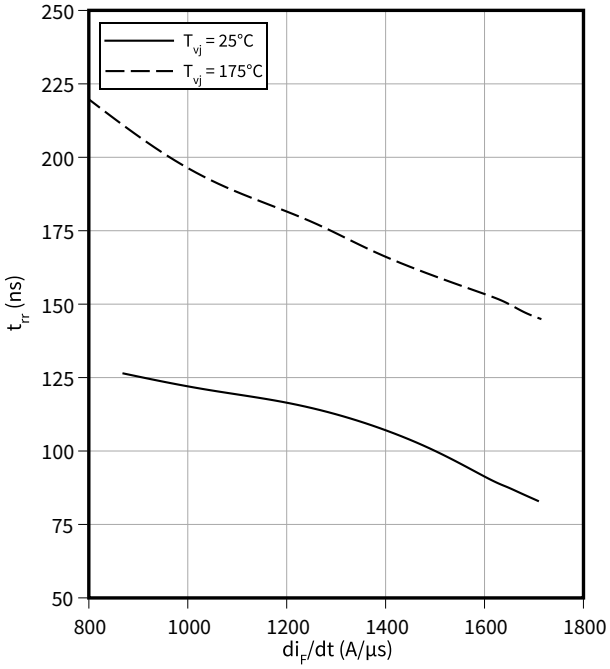
$V_F = f(T_{vj})$



Typical reverse recovery time as a function of diode current slope

$t_{rr} = f(di_F/dt)$

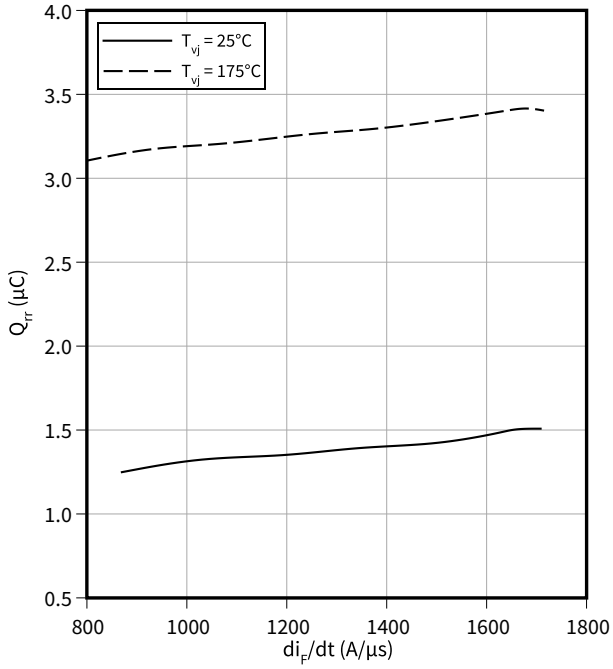
$V_R = 400\ V$, $I_F = 50\ A$



Typical reverse recovery charge as a function of diode current slope

$Q_{rr} = f(di_F/dt)$

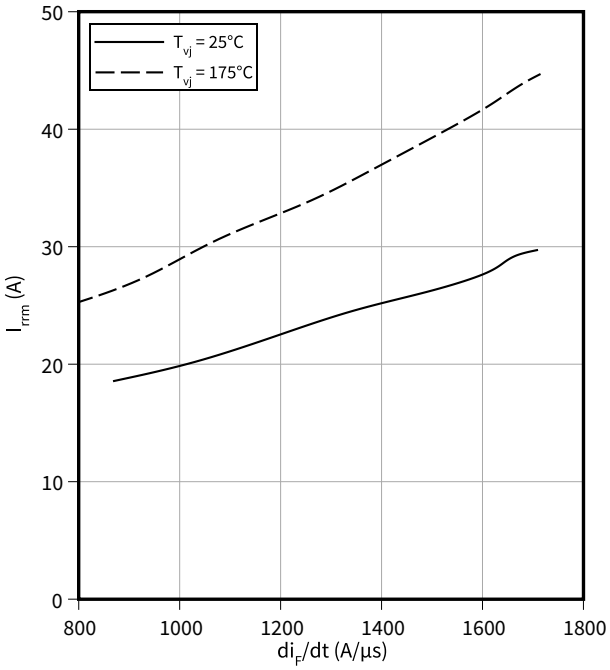
$V_R = 400\ V$, $I_F = 50\ A$



Typical reverse recovery current as a function of diode current slope

$I_{rrm} = f(di_F/dt)$

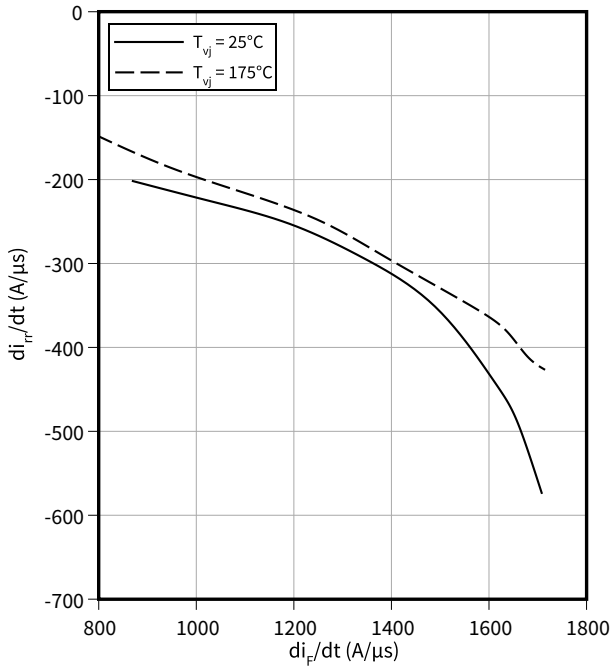
$V_R = 400\ V$, $I_F = 50\ A$



Typical diode peak rate of fall of reverse recovery current as a function of diode current slope

$di_{rr}/dt = f(di_F/dt)$

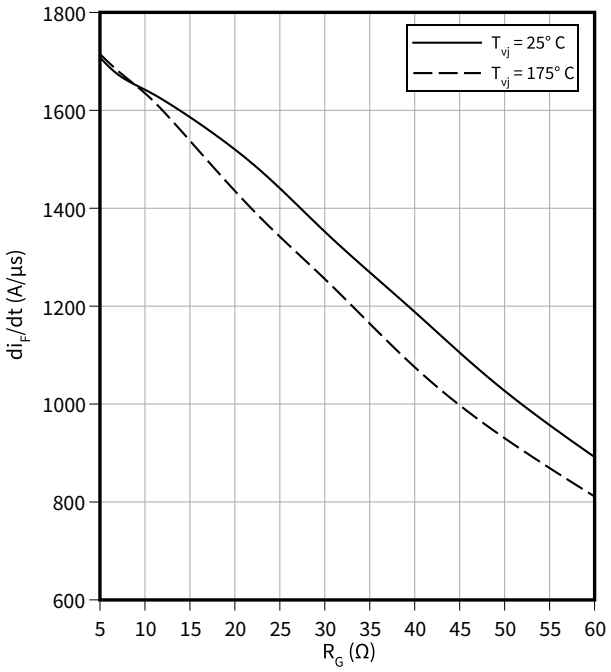
$V_R = 400\ V$, $I_F = 50\ A$



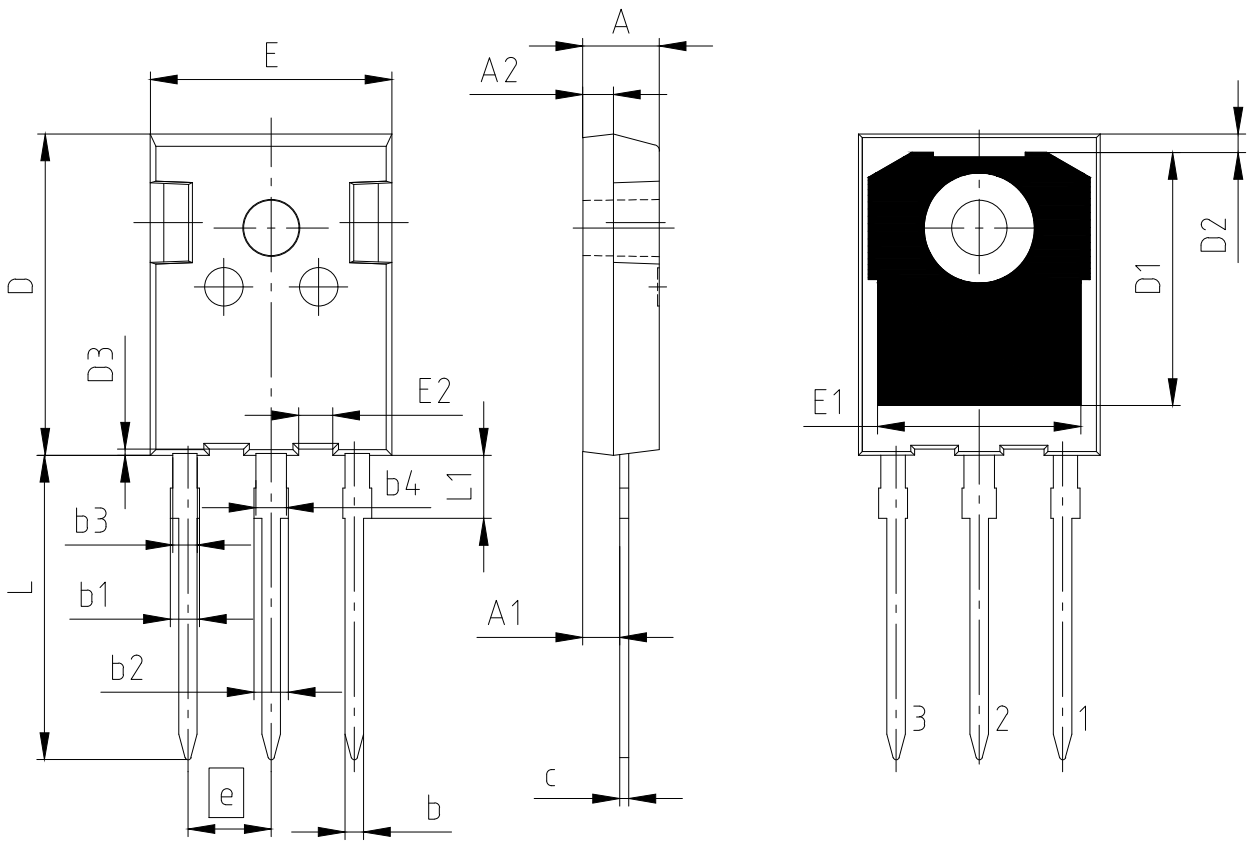
Typical diode current slope as a function of gate resistor

$di_F/dt = f(R_G)$

$V_R = 400$ V, $I_F = 50$ A



5 Package outlines



PACKAGE - GROUP NUMBER:	PG-TO247-3-U04	
DIMENSIONS	**MILLIMETERS**	
	MIN.	MAX.
A	4.90	5.10
A1	2.31	2.51
A2	1.90	2.10
b	1.16	1.26
b1		1.90
b2		2.30
b3	1.55	1.65
b4	1.96	2.06
c	0.59	0.66
D	20.90	21.10
D1	16.25	16.85
D2	1.05	1.35
D3	0.55	0.65
E	15.70	15.90
E1	13.10	13.50
E2	2.14	2.34
e	5.44	
N	3	
L	19.80	20.10
L1	3.95	4.30

Figure 1

6 Testing conditions

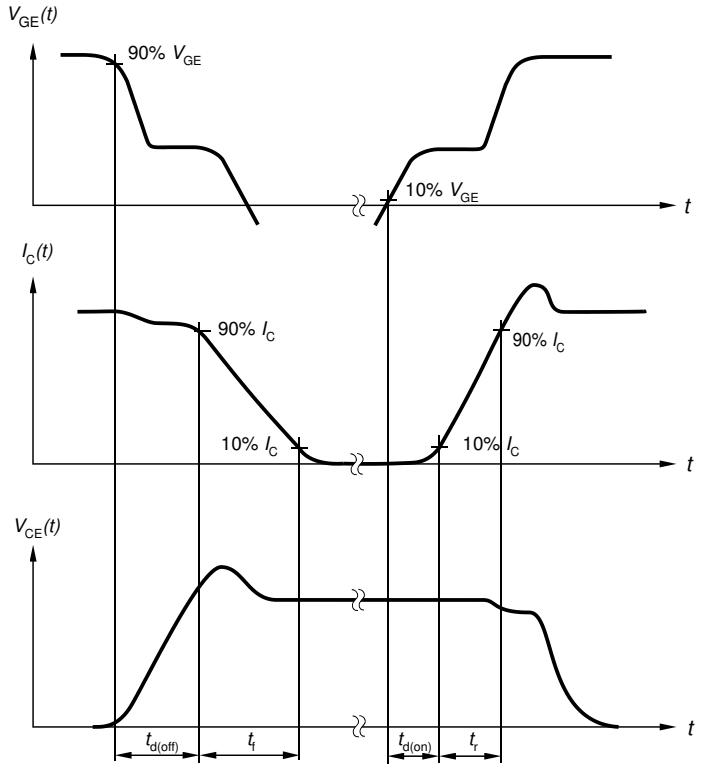


Figure A. **Definition of switching times**

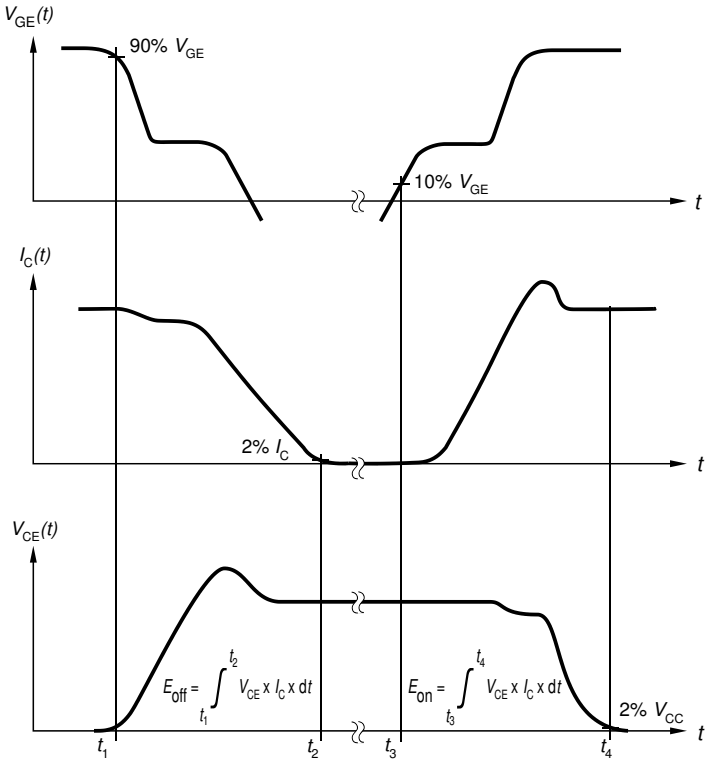


Figure B. **Definition of switching losses**

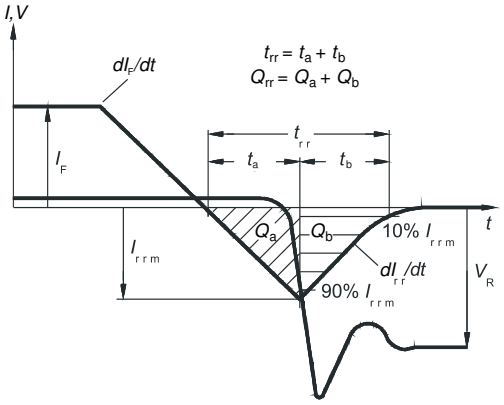


Figure C. **Definition of diode switching characteristics**

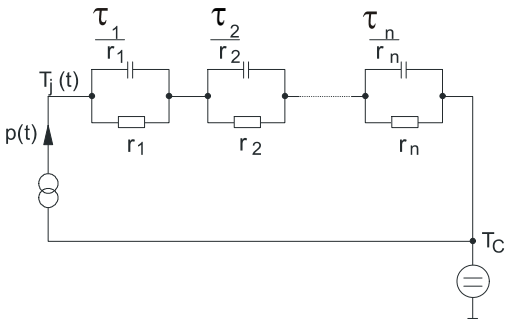


Figure D. **Thermal equivalent circuit**

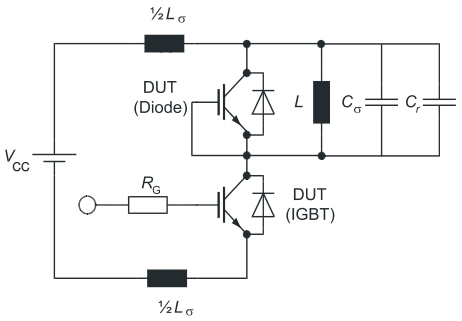


Figure E. **Dynamic test circuit**
Parasitic inductance L_σ,
parasitic capacitor C_σ,
relief capacitor C_r,
(only for ZVT switching)

Figure 2

Revision history

Document revision	Date of release	Description of changes
0.10	2025-03-19	Preliminary datasheet
1.00	2025-07-31	Final datasheet

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